

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KER ET AL.	
		10/810,645	Examiner Jeff Natalini	
			Art Unit 2858	Page 1 of 1

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	B	US-5,519,327	05-1996	Consiglio, Rosario J.	324/678
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.